

<b>Notice of References Cited</b>	Application/Control No. 10/625,491	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner N. Drew Richards	Art Unit 2815	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,458,645 B2	10-2002	DeBoer et al.	438/240
	B	US-6,605,532 B1	08-2003	Parekh et al.	438/637
	C	US-2002/0025650	02-2002	Thakur et al.	438/398
	D	US-2001/0034096	10-2001	Thakur, Randhir P. S.	438/240
	E	US-2003/0113968 A1	06-2003	Thakur, Randhir P.S.	438/253
	F	US-5,641,985	06-1997	Tamura et al.	257/530
	G	US-2003/0003632 A1	01-2003	Cleeves et al.	438/131
	H	US-6,392,284 B1	05-2002	Thakur et al.	257/530
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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